



## Dual N-Channel 30-V (D-S) MOSFET

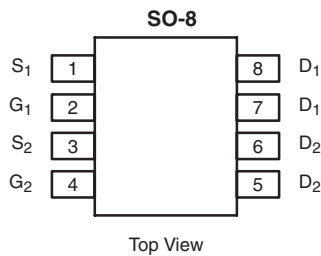
PRODUCT SUMMARY			
V <sub>DS</sub> (V)	r <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a, e</sup>	Q <sub>g</sub> (Typ)
30	0.016 at V <sub>GS</sub> = 10 V	8	19
	0.018 at V <sub>GS</sub> = 4.5 V	8	
	0.024 at V <sub>GS</sub> = 2.5 V	8	

### FEATURES

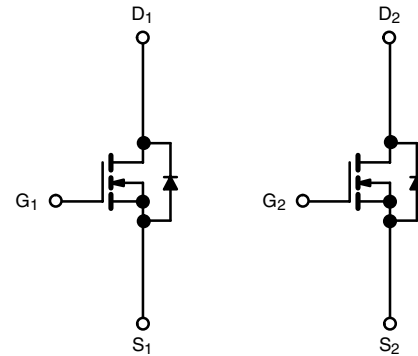
- TrenchFET<sup>®</sup> Power MOSFET
- 100 % R<sub>g</sub> and UIS tested



**RoHS**  
COMPLIANT



Ordering Information: Si4922BDY-T1-E3 (Lead (Pb)-free)



N-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T <sub>A</sub> = 25 °C, unless otherwise noted				
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V	
Gate-Source Voltage	V <sub>GS</sub>	± 12	V	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	I <sub>D</sub>	T <sub>C</sub> = 25 °C	8 <sup>e</sup>	A
		T <sub>C</sub> = 70 °C	8 <sup>e</sup>	
		T <sub>A</sub> = 25 °C	8 <sup>b, c, e</sup>	
		T <sub>A</sub> = 70 °C	6.6 <sup>b, c</sup>	
Pulsed Drain Current (10 μs Pulse Width)	I <sub>DM</sub>	35	A	
Source-Drain Current Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C	2.5	A
		T <sub>A</sub> = 25 °C	1.7 <sup>b, c</sup>	
Pulsed Source-Drain Current	I <sub>SM</sub>	35	A	
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	15	A
Single-Pulse Avalanche Energy		E <sub>AS</sub>	11.2	
Maximum Power Dissipation	P <sub>D</sub>	T <sub>C</sub> = 25 °C	3.1	W
		T <sub>C</sub> = 70 °C	2	
		T <sub>A</sub> = 25 °C	2 <sup>b, c</sup>	
		T <sub>A</sub> = 70 °C	1.28 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	- 50 to 150	°C	

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Limit		Unit	
		Typical	Maximum		
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 sec	R <sub>thJA</sub>	50	62.5	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	30	40	

Notes:

- Based on T<sub>C</sub> = 25 °C.
- Surface Mounted on 1" x 1" FR4 board.
- t = 10 sec.
- Maximum under Steady State conditions is 110 °C/W.
- Package Limited.

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$ , unless otherwise noted						
Parameter	Symbol	Test Conditions	Min	Typ <sup>a</sup>	Max	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	30			V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250\text{ }\mu\text{A}$		35		
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 4.6		
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	0.6		1.8	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{ V}, V_{GS} = \pm 12\text{ V}$			100	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 30\text{ V}, V_{GS} = 0\text{ V}$			1	$\mu\text{A}$
		$V_{DS} = 30\text{ V}, V_{GS} = 0\text{ V}, T_J = 55\text{ }^\circ\text{C}$			10	
On-State Drain Current <sup>b</sup>	$I_{D(on)}$	$V_{DS} = 5\text{ V}, V_{GS} = 10\text{ V}$	20			A
Drain-Source On-State Resistance <sup>b</sup>	$r_{DS(on)}$	$V_{GS} = 10\text{ V}, I_D = 5\text{ A}$		0.0135	0.016	$\Omega$
		$V_{GS} = 4.5\text{ V}, I_D = 5\text{ A}$		0.0145	0.018	
		$V_{GS} = 2.5\text{ V}, I_D = 5\text{ A}$		0.018	0.024	
Forward Transconductance <sup>b</sup>	$g_{fs}$	$V_{DS} = 15\text{ V}, I_D = 5\text{ A}$		30		S
<b>Dynamic<sup>a</sup></b>						
Input Capacitance	$C_{iss}$	$V_{DS} = 15\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$		2070		$\text{pF}$
Output Capacitance	$C_{oss}$			255		
Reverse Transfer Capacitance	$C_{rss}$			135		
Total Gate Charge	$Q_g$	$V_{DS} = 15\text{ V}, V_{GS} = 10\text{ V}, I_D = 5\text{ A}$		41	62	nC
		$V_{DS} = 15\text{ V}, V_{GS} = 4.5\text{ V}, I_D = 5\text{ A}$		19	29	
	3.5					
	3.7					
Gate-Source Charge	$Q_{gs}$					
Gate-Drain Charge	$Q_{gd}$					
Gate Resistance	$R_g$	$f = 1\text{ MHz}$		1.8	3	$\Omega$
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 15\text{ V}, R_L = 3\text{ }\Omega$ $I_D \cong 5\text{ A}, V_{GEN} = 10\text{ V}, R_g = 1\text{ }\Omega$		7	14	ns
Rise Time	$t_r$			27	41	
Turn-Off Delay Time	$t_{d(off)}$			31	47	
Fall Time	$t_f$			8	15	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 15\text{ V}, R_L = 3\text{ }\Omega$ $I_D \cong 5\text{ A}, V_{GEN} = 4.5\text{ V}, R_g = 1\text{ }\Omega$		13	25	
Rise Time	$t_r$			53	80	
Turn-Off Delay Time	$t_{d(off)}$			68	102	
Fall Time	$t_f$			54	81	
<b>Drain-Source Body Diode Characteristics</b>						
Continuous Source-Drain Diode Current	$I_S$	$T_C = 25\text{ }^\circ\text{C}$			2.5	A
Pulse Diode Forward Current <sup>a</sup>	$I_{SM}$				35	
Body Diode Voltage	$V_{SD}$	$I_S = 1.7\text{ A}$		0.77	1.2	V
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F = 1.7\text{ A}, di/dt = 100\text{ A}/\mu\text{s}, T_J = 25\text{ }^\circ\text{C}$		32	48	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			21	32	nC
Reverse Recovery Fall Time	$t_a$			13		ns
Reverse Recovery Rise Time	$t_b$			19		

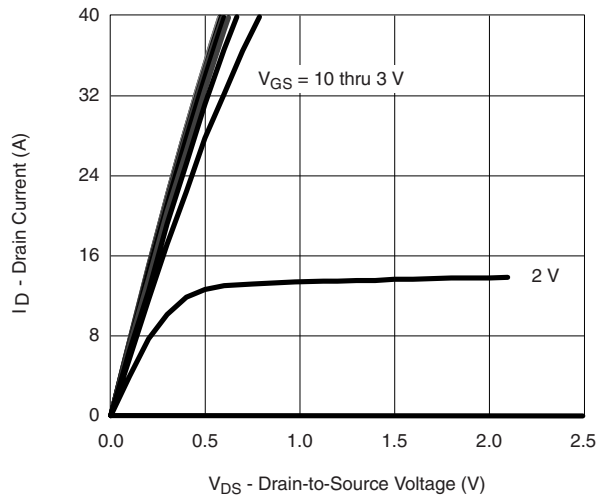
## Notes:

- a. Guaranteed by design, not subject to production testing.  
b. Pulse test; pulse width  $\leq 300\text{ }\mu\text{s}$ , duty cycle  $\leq 2\%$ .

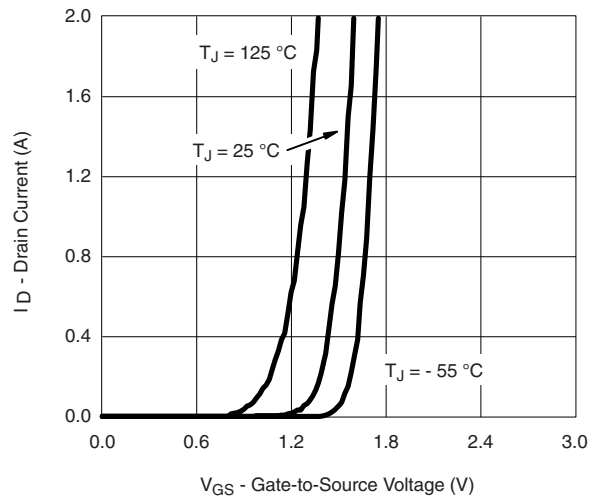
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



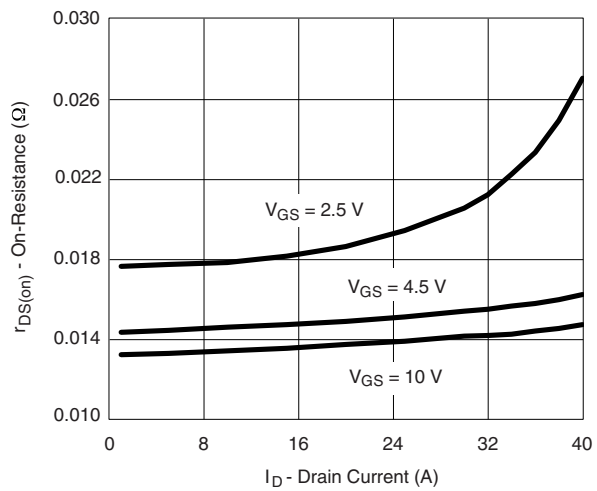
**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted



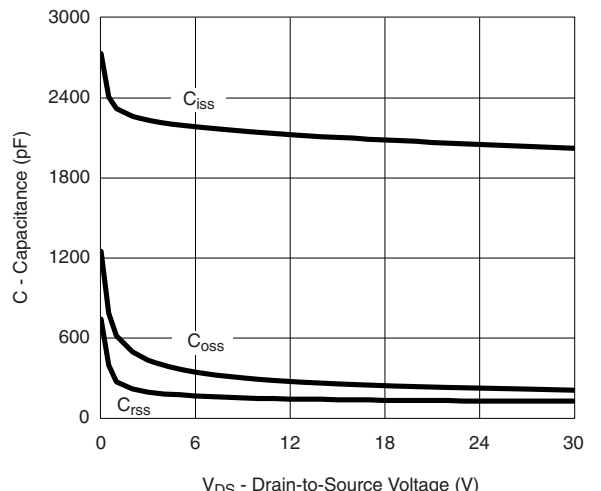
**Output Characteristics**



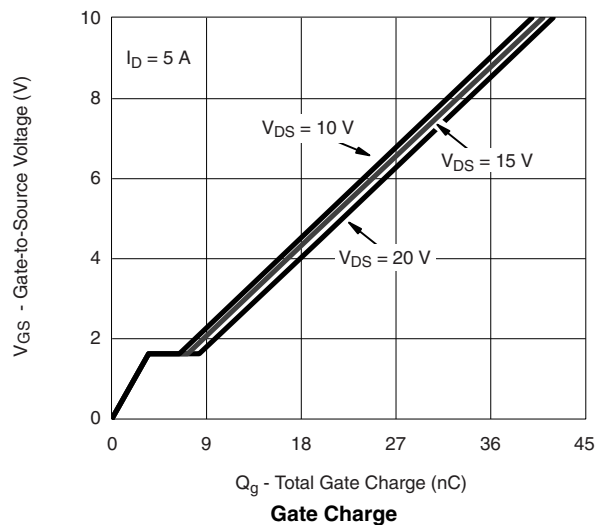
**Transfer Characteristics**



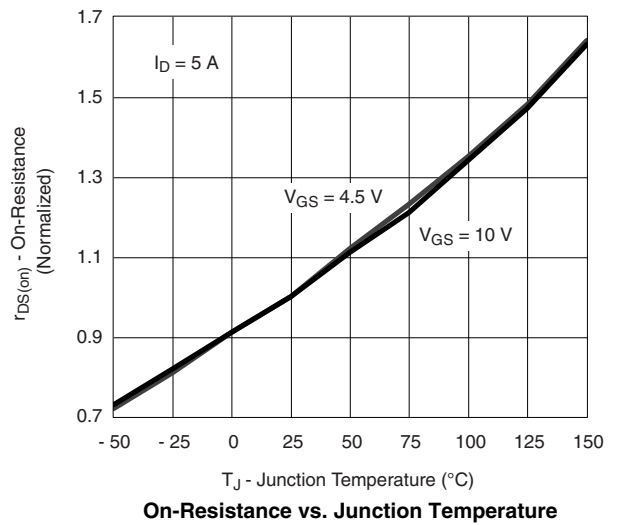
**On-Resistance vs. Drain Current and Gate Voltage**



**Capacitance**



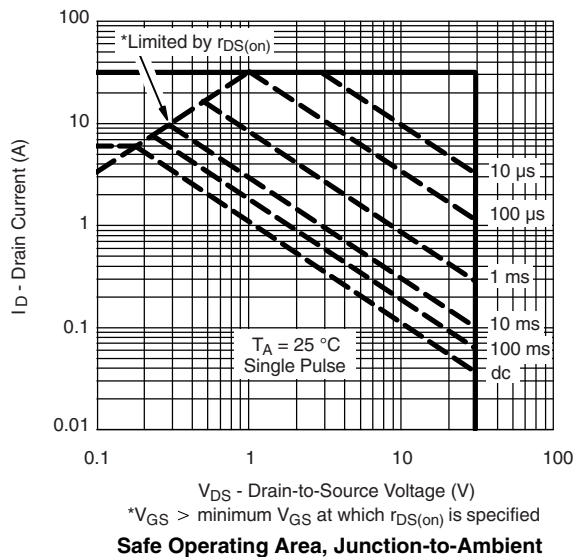
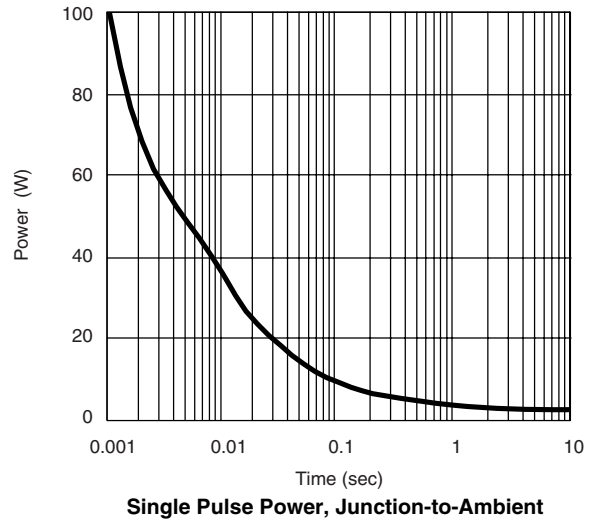
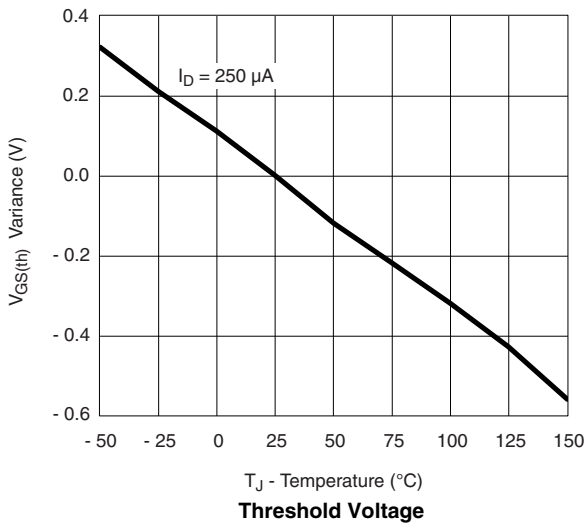
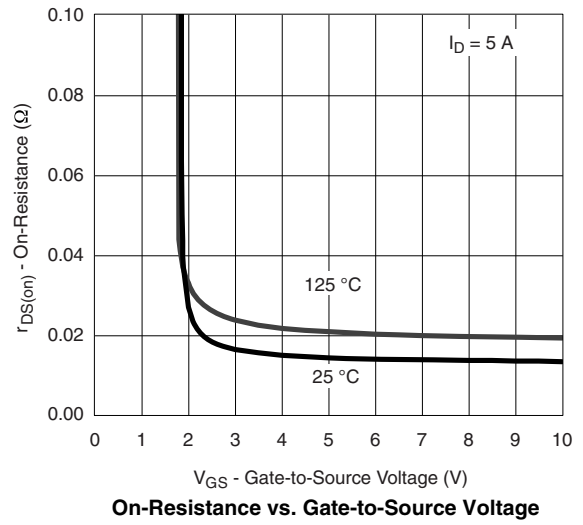
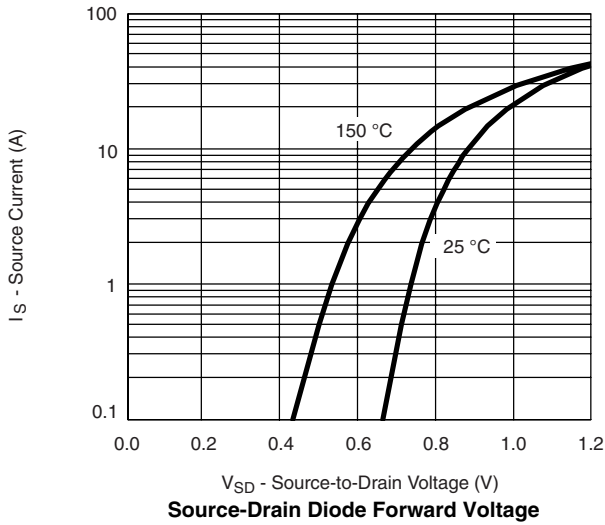
**Gate Charge**



**On-Resistance vs. Junction Temperature**

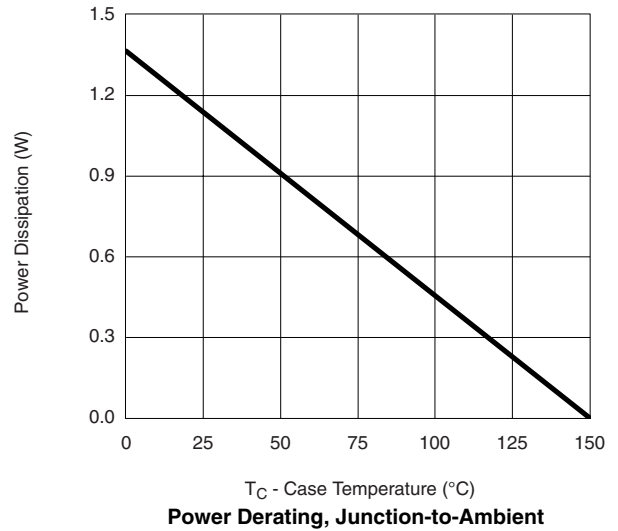
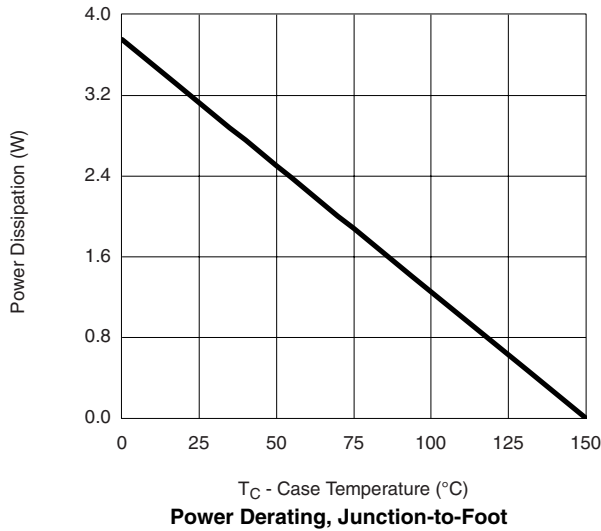
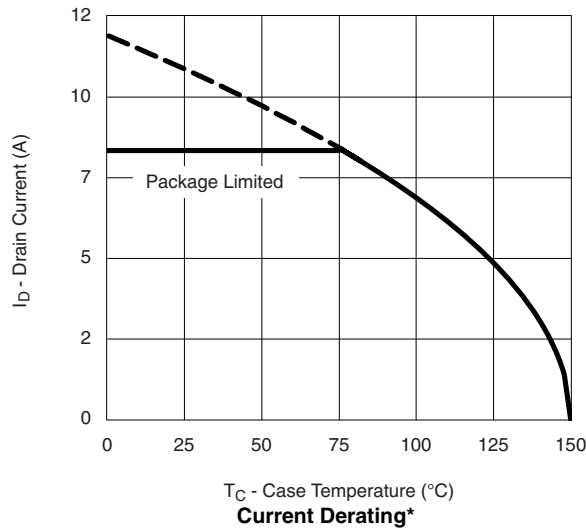


**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted





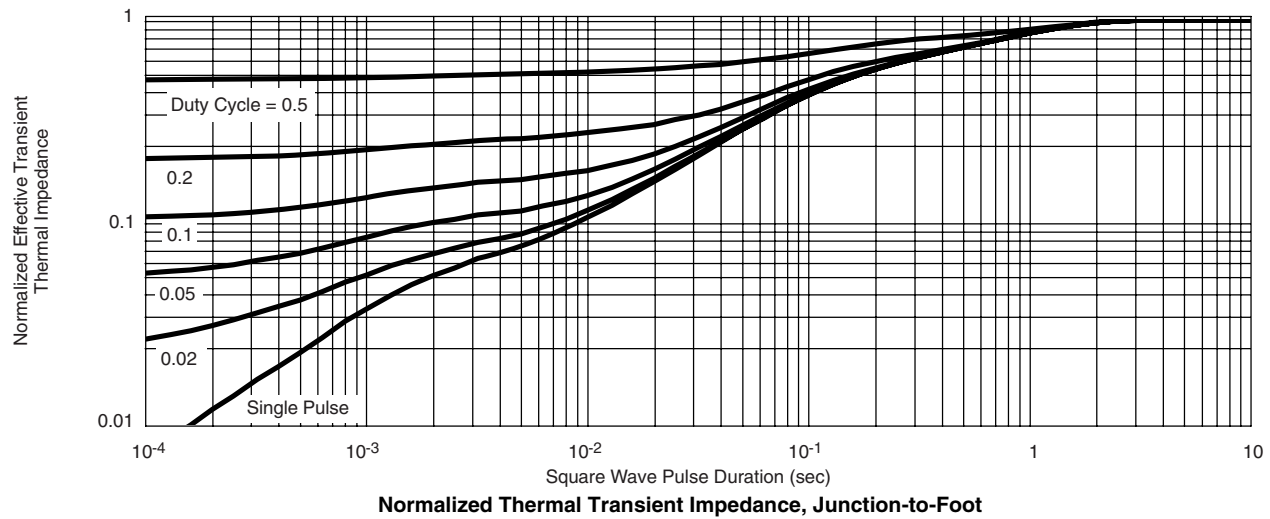
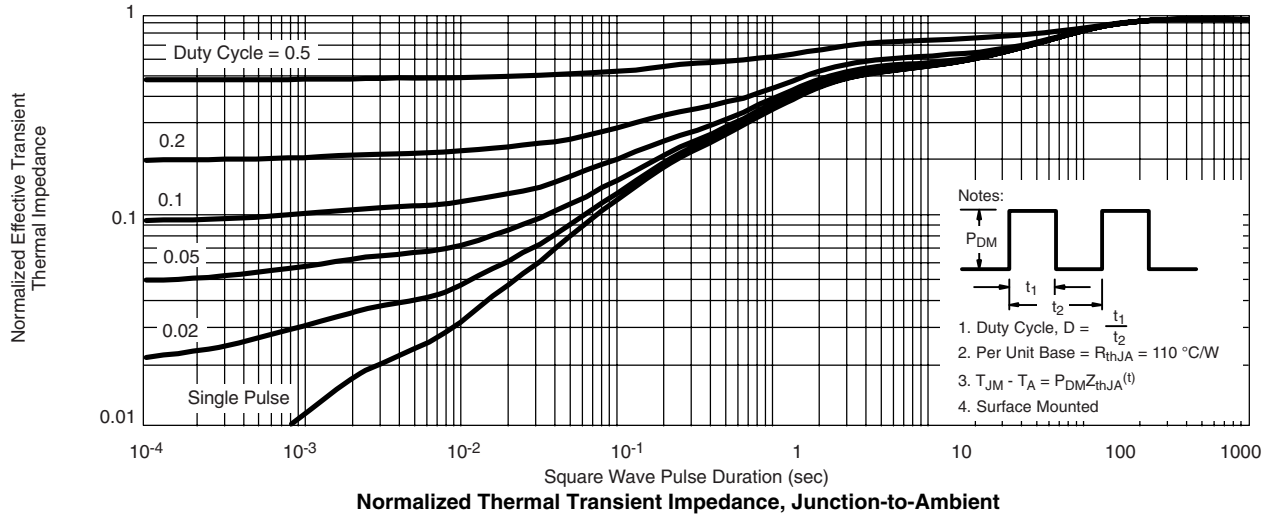
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\*The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted



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